



Radiation hardness issues in diamond

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Review of existing data on diamond radiation hardness in different operative conditions in view to develop a model of radiation damage in diamond.

Outline

- Applications of diamond in radiation environments.
- The diamond as a sensor: advantages and limits.
- Background: from the CCE to the comparison between scCVD and pCVD.
- Radiation hardness respect to:
 - · γ-rays
 - Electrons.
 - Neutrons.
 - Protons.
- Summary.

- Pions.
- Alphas.
- MeV energy ions.



Applications of diamond in radiation

environments



Diamond application is currently foreseen in many fields from fundamental to high energy physics experiments and dosimetry:

Tracking detectors:

- Strip and pixel detectors to reconstruct particle track with high spatial and energy resolution.
- A full diamond pixel module has been built for the ATLAS experiment.

Beam Condition Monitors (BCM) [1]:

- To avoid detectors damage from beam instabilities, beam condition monitoring detectors should abort safely and quickly the beam.
- Diamond has been selected for BCM at Babar, Belle, CDF, ATLAS and CMS.

Fission reactor flux monitors [2]:

- To detect neutron emitted from reactor plasmas, operating at temperatures above ambient temperature.
- Diamond sensors are developed for the International Tokamak Experimental Reactor (ITER).

^[1] Wallny et al., NIM A, 2007, Status of diamond detectors and their high energy physics application. [2] Angelone et al., NIM A, 2008, Development of single crystal diamond neutron detectors and test at JEK tokamak.



Diamond as a sensor



Advantages:

- Large band-gap:
 - → Low intrinsic charge carrier density, high resistivity: low leakage current.
- Low dielectric constant (≈1/2 of Si and GaAs):
 - → Low capacitance: low noise.
- High breakdown field:
 - → Operation at high voltages: fast charge collection.
- High mobility:
 - → Fast charge collection.
- Large thermal conductivity:
 - ⇒ Operation without cooling.
- High binding energy:
 - ⇒ Radiation hardness.

Limits:

- High energy required to create an electron-hole pair:
 - Jow signal.
- High density of defects:
 - → Charge trapping and recombination: unable to collect all the produced ionization signal.
 - ⇒ Polarization effect.







Parameters characterizing performances:

- Charge Collection Efficiency (CCE): $CCE = \frac{Q_{measured}}{Q_{deposited}}$
 - Charge Collection Distance (CCD):

$$CCD = (\mu_n \tau_n + \mu_p \tau_p)E = \frac{Q_{measured}}{Q_{deposited}} * thickness = \frac{Q_{measured}[e]}{36[e / \mu m]}$$

- Short-time radiation effects (especially for pCVD):
 - Priming or pumping: increase of the CCE (CCD) during the irradiation with ionising particles due to the filling of vacant trap sites (passivation) [3]:

$$CCE(D) = CCE(D=0) + (R_p - 1)CCE(D=0) \left(1 - e^{-\frac{D}{D_0}} \right)$$

• R_p : priming ratio; D_0 : priming dose.

• Polarization effects: building of a non uniform electric field due to the localized filling of the traps.













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scCVD and pCVD – Results of the RD42 collaboration

Radiation hardness with respect to 24GeV/c proton irradiation:

$$\frac{1}{CCD} = \frac{1}{CCD_0} + k\phi$$

- k≈10⁻¹⁸ cm
- scCVD shifted by 3.8x10¹⁵cm⁻²









Motivations:

- Low-angle detectors for TESLA linear accelerator project [6]: detector at 1.2 cm from the beam line, dose of as much as 1 MGy per year.
- Materials and methods:
 - pCVD diamond from DeBeers, with Ti-Pt-Au contacts.
 - Irradiations: 10 keV photon beam and ⁶⁰Co source (1.17 and 1.33 MeV).
 - CCD and TSC measurements before and after radiation (primed samples, voltage for maximum carrier velocity).
 - Measurement of the TSC peak and of the CCD respect to the non irradiated samples.

[5] Behnke et al., NIM A, 2002, Electromagnetic radiation hardness of diamond detectors. [6] Behnke et al., R. Settles (Eds.), 2001, TESLA technical design report, Part IV: A detector for TESLA.



10 keV y-rays on pCVD





- TSC peak increase with the bias accordingly to the increasing mobility.
- No effect of the irradiation on the TSC: same concentration of induced defects.
- No degradation of the CCD for any energy and dose.
- No radiation damage problem in diamond for applications like TESLA.

[5] Behnke et al., NIM A, 2002, Electromagnetic radiation hardness of diamond detectors.







Motivations:

- At the International Linear Collider (ILC), the innermost calorimeter, the BeamCal, is hit by a huge amount of electron-positron pairs.
 Sensors are interspersed between the absorber planes to obtain information about the collision and provide a feedback for the steering.
- The Total Ionizing Dose (TID) can accumulate to several MGy/year: radiation hardness is mandatory.
- Materials and methods:
 - pCVD diamonds from two manufacturers with Ti-Pt-Au contacts.
 - Irradiation with 10 MeV electrons up to a TID of several MGy (S-DALINAC, Darmstadt) and comparison with 4 GeV hadrons (PS, CERN).
 - Measurement of the CCD before and after irradiation.
 - Comparison with silicon detector (3-5 k Ω cm resistivity).

[14] Grah et al., IEEE TNS, 2009, Polycristalline CVD diamonds for the beam calorimeter of the ILC.





Results: CCD and I-V



Initial pumping, then CCD down to a level comparable with the initial unpumped state.

- The current is still in the order of few pA after irradiation, thus is uncritical for operations as a detector. (In the Si detector it increases up to more than 6 uA.)
- The silicon detector is much less radiation hard.

[14] Grah et al., IEEE TNS, 2009, Polycristalline CVD diamonds for the beam calorimeter of the ILC.







Motivations:

- Test radiation hardness and predict the radiation induced damage with a model.
- Materials and methods:
 - pCVD diamond compared to Si.
 - Neutrons from 10 keV to 20 MeV up to 1.6×10^{16} n/cm².
 - Measurement of the leakage current in time during the exposure and of the CCD after irradiation. Measurement of the maximum CCE in the primed state.
 - CCE vs. fluence empirical model [3]:

$$CCE(\phi) = CCE(\phi = 0) \left[r_n \left(1 - \frac{\phi}{\alpha_{n1}} \right) + (1 - r_n) e^{-\frac{\phi}{\alpha_{n2}}} \right]$$

- r_n : ratio of the CCE loss due to the linear part to the total.
- α'_{n1} , α_{n2} : damage constants.

[3] Oh et al., DRM, 2000, Neutron irradiation studies with detector grade CVD diamond.



1 MeV neutrons on pCVD

1.0



TSC signal

Results:





Fluence [n/cm²]

Fig. 1. TSC signal vs. temperature for non-irradiated and irradiated samples, after filling with UV xenon lamp for 20 min. The samples are biased with 100 V. The heating rate is 0.15 K/s. The neutron fluences are indicated in the legend.

Fig. 5. Normalised TSC and TL signal vs. fluence obtained by the integral of the TSC and TL signal as a function of the temperature, dividing by the heating rate and normalising to the value corresponding to the non-irradiated sample.

1 MeV neutrons deactivate high temperature electrically active defects.
 This corresponds to have faster dynamics in dosimetry (see M. Bruzzi talk).

[7] Bruzzi et al., DRM, 2001, Electrical properties and defect analysis of neutron irradiated undoped CVD diamond films.

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Spallation neutrons on pCVD



Results (from 10 keV to 10 MeV peaked at 5 MeV)



In diamond, very low and stable leakage current (\approx 300 pA) correlated to the neutron (or γ -background) flux. In silicon, the current increases (up to \approx 10 uA) due to radiation induced defects creation.

The CCD of diamond slightly decrease before 10¹⁵ n/cm².

[4] RD42, CERN EP, 1998, Development of CVD diamond radiation detectors.



CCE decrease (as modelled) due to increasing defect concentration. Resistivity decreases because defects increases the free carrier concentration (but not a severe problem: $>5x10^{11} \Omega cm!!!$).

- Samples behave differently: explained by different defects introduction rate.
- [3] model also priming, introduction rate, depth dependence.

[3] Oh et al., DRM, 2000, Neutron irradiation studies with detector grade CVD diamond. R. Mori, M. Bruzzi ADAMAS, 16-18 December 2012, GSI



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20 MeV neutrons on pCVD



Results: ionization signal



The signal decrease of 50% after (1.25±0.25)x10¹⁵ n/cm². Twofold exponential decay (see [9]).

[8] de Boer et al., PSS, 2007, Radiation hardness of diamond and silicon sensors compared. [9] Muller, Diploma thesis, 2006, University of Karlsruhe.

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Motivations:

- Test the radiation hardness for LHC experiments.
- Compare diamond with silicon performance with respect to proton irradiation.
- Materials and methods:
 - pCVD diamond samples with Cr-Au contacts and scCVD with Au contacts.
 - Irradiation with protons with 500 MeV kinetic energy (TRIUMF, Canada), 24 GeV/c momentum (PS, CERN), 26 MeV, 2.6 MeV (40 um penetration depth), up to 18x10¹⁵ p/cm².
 - Measurement of charge signal distribution, CCD and of particle-induced current during irradiation. IBIC (Ion Beam Induced Charge) on scCVD to measure the CCE with 2.6 MeV protons.





Results: CCD and current for 24 GeV/c protons

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- Diamond is radiation hard up to 2x10¹⁵ p/cm².
- Particle-induced current in diamond doesn't change in time.
- The OFF-spill current in diamond is negligible, while in silicon increases over 100 uA indicating radiation damage.

[10] RD42, NIM A, 1999, Proton irradiation of CVD diamond detectors for high-luminosity experiments at the LHC.

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24 GeV/c protons on pCVD



Results: signal distribution for 24 GeV/c protons



MPV decrease of 20% only at 5x10¹⁵ p/cm². Exponential decay of the signal with irradiation. "Radiation lifetime" is 12.5x10¹⁵ p/cm².

Pumping effect for 0.9x10¹⁵ p/cm², radiation damage dominate over 3x10¹⁵ p/cm².

The pulse height distribution agree with a model [12] accounting for the pumping and the radiation damage.

[11] RD42, NIM A, 2000, Pulse height distribution and radiation tolerance of CVD diamond detectors. [12] Adam et al., NIM A, 2006, Radiation hard diamond sensors for future tracking applications.



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Results: 26 MeV protons



Signal decrease more rapidly respect to higher energetic protons and neutrons.

[8] de Boer et al., PSS, 2007, Radiation hardness of diamond and silicon sensors compared.



2.6 MeV protons on scCVD



Results: 2.6 MeV protons



- Reduction of 50% of the CCE already at 10¹³ p/cm².
- 2.6 MeV protons (Bragg peak at about 40 um) leave localized damage which influence the CCE, by trapping charges and reducing the field strength in the undamaged material for polarization effects.

[13] Lohstroh et al., PSS, 2008, Ion beam induced charge (IBIC) irradiation damage study in synthetic single crystal diamond using 2.6 MeV protons.







Motivations:

- Study the radiation hardness for the LHC.
- Materials and methods:
 - pCVD diamonds with Cr-Au contacts.
 - Irradiation with 300 MeV/c pions (correspondingly to the peak of the pion-nucleon cross section) up to $1.7 \times 10^{15} \, \pi/cm^2$.
 - Measurement of the particle-induced current and CCD.
 - · Comparison with silicon detector.

[4] RD42, CERN EP, 1998, Development of CVD diamond radiation detectors. [15] Bauer et al., NIM A, 1996, Recent results from the RD42 diamond detector collaboration.



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300 MeV/c pions on pCVD



Results:



- Diamond doesn't show increase of the leakage current after irradiation.
- Pumping effect for low fluences.
- Detector performances unchanged up to $1.7x10^{15} \pi/cm^2$.

[4] RD42, CERN EP, 1998, Development of CVD diamond radiation detectors. [15] Bauer et al., NIM A, 1996, Recent results from the RD42 diamond detector collaboration.

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Motivations:

- Study of the radiation hardness.
- Materials and methods:
 - pCVD diamonds with Cr-Au contacts.
 - Irradiation with 5 MeV alpha particles (12 um penetration depth) up to $2x10^{15} \alpha/cm^2$.
 - Measurement of the CCD by means of surface photo-induced conductivity measurements.

[15] Bauer et al., NIM A, 1996, Recent results from the RD42 diamond detector collaboration.





20% CCD decrease after only 2x10^{13} \alpha/cm^2.

[15] Bauer et al., NIM A, 1996, Recent results from the RD42 diamond detector collaboration.

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- Motivations:
 - At high energy hadron colliders, secondary interactions produce a significant fraction of particles in this range.
 - Reducing the range result in an increase of defect concentration, which is no longer homogeneous.
 - The radiation hardness cannot be simply extrapolated from the higher energy range.
- Materials and methods:
 - scCVD diamonds with diamond-like carbon film plus Pt-Au contacts and silicon PIN diode.
 - Carbon ions as damaging particles (avoid the implantation of foreign atoms).
 - Microprobe single ion technique IBIC (Ion Beam Induced Charge) to measure the CCE.

[16] Zamboni et al., DRM, 2012, Radiation hardness of single crystal CVD diamond detector tested with MeV energy ions.



MeV energy ions on scCVD





- The detector energy resolution increase with the applied bias.
- Hole CCE deteriorate faster due to the more efficient hole trapping by carbon ion produced stable defects or less efficient electron trapping due to additionally produced donor centers.

[16] Zamboni et al., DRM, 2012, Radiation hardness of single crystal CVD diamond detector tested with MeV energy ions. R. Mori, M. Bruzzi ADAMAS, 16-18 December 2012, GSI





Results: comparison with silicon

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Same energy: over the entire carbon fluence range, silicon CCE is higher than diamond CCE.

Same loss rate: higher CCE deterioration rate for silicon but still better than diamond.

[16] Zamboni et al., DRM, 2012, Radiation hardness of single crystal CVD diamond detector tested with MeV energy ions.

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- Irradiation with C ions produce more hole traps or donor centers, as suggested by the higher hole CCE deterioration.
- Radiation at MeV energies produce higher defect concentration in a small volume, decreasing local lifetime by increasing trapping probability. It influences the overall CCE more respect to an homogeneous irradiation.
 - For 6.5 MeV C ions, the simulations give four times more vacancies in silicon than in diamond, but results show lower radiation hardness of diamond:
 - Much higher mobility and recombination of defects in silicon at RT that reduce the net concentration.
 - Stronger influence of polarization effects in damaged regions of diamond.

[16] Zamboni et al., DRM, 2012, Radiation hardness of single crystal CVD diamond detector tested with MeV energy ions.







Diamond is currently planned for fundamental and high energy physics experiments as a tracking detector, beam condition monitor, fission reactor flux monitor, etc..

- It should withstand an high radiation environment maintaining its unique properties such as fast response, collection efficiency, energy resolution. Radiation hardness is a fundamental property.
- In the last 15 years, diamond radiation damage has been tested with γ -rays, neutrons, protons, electrons, pions, alphas and low energetic ions.
- Results show diamond is radiation hard up to several MGy of photons and electrons, up to 10¹⁵ (neutrons and high energetic protons)/cm² and >10¹⁵ pions /cm². In such conditions, leakage current remains negligible and CCD decreases only slightly.
- Apart for low energetic ions, silicon detectors appear to be much less radiation hard than diamond in terms of CCE.
- Radiation damage in diamond is more significant for low energetic protons, neutrons, alphas and MeV ions.
- Most of the studies are for pCVD due to historical reasons, more tests on scCVD are required!
- A model on radiation hardness should account for different particles and energy (NIEL) .
- More systematic studies on radiation induced defects and simulations are required to get to it. Thank you for your attention!!!







- Properties of the scCVD vs. thickness.
- Modeling of the CCD with pumping effect.
- MeV energy ions: penetration.
- NIEL damage cross section.
- Particles damage on silicon.





Properties vs. thickness:

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[12] Adam et al., NIM A, 2006, Radiation hard diamond sensors for future tracking applications. R. Mori, M. Bruzzi ADAMAS, 16-18 December 2012, GSI





$$\frac{1}{CCD(\phi)} = \frac{1 - \delta + \delta e^{-\gamma\phi}}{CCD(0)} + k\phi$$

- δ : fraction of the traps which can be passivated.
- γ: passivation constant.



10

penetration depth (µm)

100

[16] Zamboni et al., DRM, 2012, Radiation hardness of single crystal CVD diamond detector tested with R. Mori, M. Bruzzi ADAMAS, 16-18 December 2012, GSI

0.1





The NonIonizing Energy Loss (NIEL) express the rate of energy loss due to atomic displacement as a particle transverses the material.

The Kinetic Energy Released in MAtter (KERMA) is expressed by:

KERMA (keV)=NIEL(keV*cm²/gm)* ϕ (cm⁻²)*mass(gm).

Here it is shown the Displacement damage cross section (in Si 100 MeVmb=2.144 keV*cm²/gm).



[8] de Boer et al., PSS, 2007, Radiation hardness of diamond and silicon sensors compared. R. Mori, M. Bruzzi ADAMAS, 16-18 December 2012, GSI



Particles damage on silicon



Initial distribution of vacancies in $(1\mu m)^3$ after 10^{14} particles/cm² **10 MeV protons** 24 GeV/c protons **1 MeV neutrons** 36824 vacancies 4145 vacancies 8870 vacancies y (µm) 0.8 0.6 0.4 0.2 0 0.5 0.5 0 0.5 0 1 0

x (µm)

[17] Huhtinen, NIM A, 2002.

x (µm)

x (µm)